

## NVNA Users' Forum

Taormina, Italy – co-located with INMMiC

Oct. 1<sup>st</sup>, 2015, 17:40-18:40

Organizers: Dominique Schreurs, Patrick Roblin

### Agenda:

- Research Update:  
Giovanni D'Amore (Keysight Technologies, USA): *“DynaFET modeling flow for GaN and GaAs devices”*
- IEEE Standards:  
Dominique Schreurs (KU Leuven, Belgium): *“Latest developments on IEEE standardization efforts: NVNA nomenclature and EVM definition”*
- Discussion Topic:  
Patrick Roblin (The Ohio State University, USA):  
*“Comparing of the pros and cons of PA design techniques based on:  
- simulation using circuit-based device model  
- conventional RF load-pull and X-parameters  
- nonlinear embedding”*